

<b>Notice of References Cited</b>	Application/Control No. 10/623,356	Applicant(s)/Patent Under Reexamination MCCUTCHEN, DAVID L.	
	Examiner Terrence R. Till	Art Unit 1744	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-1,784,339	12-1930	FRIEDRICH CLASEN; et. al.	55/288
	B	US-3,653,190	04-1972	Lee et al.	55/302
	C	US-3,735,566	05-1973	Laliwala, Jitendra R.	96/427
	D	US-4,329,161	05-1982	Osborn, Jack	95/280
	E	US-4,465,497	08-1984	Howeth, David F.	96/427
	F	US-4,533,371	08-1985	Nakamura, Katsutoshi	55/299
	G	US-4,618,352	10-1986	Nelson, Robert T.	55/287
	H	US-5,868,807	02-1999	Luy et al.	55/302
	I	US-5,948,127	09-1999	Minakawa et al.	55/283
	J	US-2002/0194996	12-2002	Peter et al.	95/278
	K	US-2003/0041729	03-2003	Finigan, Justin J.	95/26
	L	US-2003/0089234	05-2003	Bjarno et al.	95/280
	M	US-6,830,599	12-2004	McCutchen, Clinton J.	55/283

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.